

Notice of References Cited

Application/Control No.

10/573,810

Applicant(s)/Patent Under

Reexamination

MIYADERA ET AL.

Examiner

JOHN M. BEDTELYON

Art Unit

2874

Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2003/0202746	10-2003	Hanashima, Naoki	385/45
*	B US-7,302,138	11-2007	Lu, Hung-Chih	385/37
*	C US-7,088,889	08-2006	Takahashi et al.	385/43
*	D US-6,970,625	11-2005	Johannessen et al.	385/45
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.